

This Page Is Inserted by IFW Operations
and is not a part of the Official Record

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

IMAGES ARE BEST AVAILABLE COPY.

**As rescanning documents *will not* correct images,
please do not report the images to the
Image Problem Mailbox.**

Date Searched: 6/18/2002

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 716/\$.ccls. and (self adj heat\$3)

Results: 4 hits

L2 (((716/\$.ccls.or 257/758.ccls or 438/637.ccls.) and (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)) and (layout or placement or floorplan\$4 or floor-plan\$4)) and (overlap\$4 same row) and @pd>20010910

Resultss: 0 hit

L3 (signal same (integrity or reliability)) and (electromigrat\$4 or (self adj heat\$4) or (hot adj electron)) and (716/\$.ccls.or 257/758.ccls or 438/637.ccls.) and @pd>20010910

Results: 3 hits

US 6308303 B1 USPAT Mysore, Sriram et al. 716/5

US 6308302 B1 USPAT Hathaway, David James et al. 716/5

Database Searched: IEEE/IEEE

Terms Searched: microprocessor and (elctromigration or (self <near/2> heat*))

Results: Your search matched 3 of 775001 documents.

Date Searched: 9/17/2001

Database Searched: USPAT

Plurals: ON

Terms Searched:

L1 transistor same folding

L2 electromigrat\$4 or (electro adj migrat\$4)

L3 1 and 2

Results: 1 hit

L4 1 and 716/\$.ccls.

Results: 20 hits

L5 signal same (reliability or integrity)

L6 1 and 5

Results: 6 hits

US 5751180 A USPAT D'Addeo, Michael Lee 327/379

US 6163877 A USPAT Gupta, Avaneendra 716/8

US 6077308 A USPAT Carter, Craig A. , et al. 716/8

US 5995734 A USPAT Saika, Shunji 716/9

US 5737236 A USPAT Maziasz, Robert , et al. 716/8

US 5675501 A USPAT Aoki, Sachiko 716/8

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 transistor same folding

L2 electromigrat\$4 or (electro adj migrat\$4)

L3 1 and 2

Results: 0 hits

L4 signal same (reliability or integrity)

L5 1 and 4

Results: 2 hits

JP 60197034 A A JPO YAMAMOTO, YOSHINOBU , CHIBA, TAKASHI , et al.

Date Searched: 9/10/2001

Database Searched: USPAT

Plurals: ON

Terms Searched:

L1 716/\$.ccls.

L2 (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)

L3 layout or placement or floorplan\$4 or floor-plan\$4

L4 1 and 2 and 3

Results: 214 hits

L5 (electromigrat\$4 or electro-migrat\$4) and self-heat\$4

L6 1 and 3 and 5

Results: 0 hits

L7 overlap\$4 same row

L8 4 and 7

Results: 6 hits

L9 signal same (integrity or reliability)

L10 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)

L11 1 and 9 and 10

Results: 4 hits

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 (signal or constraint or cost) same (integrity or reliability)

L2 layout or placement or floorplan\$4 or floor-plan\$4

L3 1 and 2

Results: 248 hits

L4 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)

L5 3 and 4

Results: 1 hits

L6 1 and 4

Results: 40 hits

US 6002857 A USPAT Ramachandran, Venkateswaran ("Venky") 716/14

US 5984510 A USPAT Guruswamy, Mohan , et al. 716/2

US 6286128 B1 USPAT Pileggi, Lawrence , et al. 716/18

US 6038383 A USPAT Young, Duane J. , et al. 716/5

US 6253361 B1 USPAT Buch, Premal 716/6

US 5737580 A USPAT Hathaway, David James , et al. 716/12

US 6195787 B1 USPAT Yokoyama, Moto 716/8

US 5822218 A USPAT Moosa, Mohamed S. , et al. 716/4

US 5648910 A USPAT Ito, Soichi 716/2

JP 2000206201 A A JPO FURUE, KATSUYA

JP 08293532 A A JPO NISHIMURA, KOICHI

JP 06302703 A A JPO YAMADA, TATSUYA , KATO, YOSHIAKI

JP 03149823 A A JPO MATSUOKA, FUMITOSHI

US 6242807 B1 USPAT Kazami, Tetsuo 257/758

Database Searched: IEE/IEEE

Terms Searched: (signal or constraint or cost) and (integrity or reliability) and (layout or placement or floorplan* or floor-plan*) and (electromigrat* or (self <near/2> heat*))

Results: Your search matched 4 of 713260 documents.

Terms Searched: (integrity or reliability) and (layout or placement or floorplan* or floor-plan*) and (electromigrat* or (self <near/2> heat*))

Results: Your search matched 19 of 713260 documents.

Terms Searched: (transistor <near/4> folding) and (signal <near/10> (reliability or integrity))

Results: Your search matched [0] of [714343] documents.

Terms Searched: (transistor <near/4> folding)

Results: Your search matched 24 of 714315 documents.

Date Searched: 9/17/2001
Database Searched: USPAT
Plurals: ON

Terms Searched:

L1 transistor same folding
L2 electromigrat\$4 or (electro adj migrat\$4)
L3 1 and 2
Results: 1 hit
L4 1 and 716/\$.ccls.
Results: 20 hits
L5 signal same (reliability or integrity)
L6 1 and 5
Results: 6 hits

US 5751180 A USPAT D'Addeo, Michael Lee 327/379

upta, A.; Siang-Chun The; Hayes, J.P. "XPRESS: A Cell Layout Generator with Integrated Transistor Folding ", European Design and Test Conference, 1996.

ED&TC96. Proceedings, 1996, pp. 393-400.*

US 6163877 A	USPAT Gupta, Avaneendra	716/8
US 6077308 A	USPAT Carter, Craig A. , et al.	716/8
US 5995734 A	USPAT Saika, Shunji	716/9
US 5737236 A	USPAT Maziasz, Robert , et al.	716/8
US 5675501 A	USPAT Aoki, Sachiko	716/8

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 transistor same folding
L2 electromigrat\$4 or (electro adj migrat\$4)
L3 1 and 2
Results: 0 hits
L4 signal same (reliability or integrity)
L5 1 and 4
Results: 2 hits

JP 60197034 A A JPO YAMAMOTO, YOSHINOBU , CHIBA, TAKASHI , et al.

Date Searched: 9/10/2001
Database Searched: USPAT
Plurals: ON

Terms Searched:

L1 716/\$.ccls.
L2 (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)
L3 layout or placement or floorplan\$4 or floor-plan\$4
L4 1 and 2 and 3
Results: 214 hits
L5 (electromigrat\$4 or electro-migrat\$4) and self-heat\$4
L6 1 and 3 and 5
Results: 0 hits
L7 overlap\$4 same row
L8 4 and 7
Results: 6 hits

L9 signal same (integrity or reliability)
 L10 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)
 L11 1 and 9 and 10
 Results: 4 hits

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 (signal or constraint or cost) same (integrity or reliability)

L2 layout or placement or floorplan\$4 or floor-plan\$4

L3 1 and 2

Results: 248 hits

L4 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)

L5 3 and 4

Results: 1 hits

L6 1 and 4

Results: 40 hits

US 6002857 A	USPAT Ramachandran, Venkateswaran ("Venky")	716/14
US 5984510 A	USPAT Guruswamy, Mohan , et al.	716/2
US 6286128 B1	USPAT Pileggi, Lawrence , et al.	716/18
US 6038383 A	USPAT Young, Duane J. , et al.	716/5
US 6253361 B1	USPAT Buch, Premal	716/6
US 5737580 A	USPAT Hathaway, David James , et al.	716/12
US 6195787 B1	USPAT Yokoyama, Moto	716/8
US 5822218 A	USPAT Moosa, Mohamed S. , et al.	716/4
US 5648910 A	USPAT Ito, Soichi	716/2
JP 2000206201 A	A JPO FURUE, KATSUYA	
JP 08293532 A A	JPO NISHIMURA, KOICHI	
JP 06302703 A A	JPO YAMADA, TATSUYA , KATO, YOSHIAKI	
JP 03149823 A A	JPO MATSUOKA, FUMITOSHI	
US 6242807 B1	USPAT Kazami, Tetsuo	257/758
US 5817574 A	USPAT Gardner, Donald S.	438/637

Database Searched: IEE/IEEE

Terms Searched: (signal or constraint or cost) and (integrity or reliability) and (layout or placement or floorplan* or floor-plan*) and (electromigrat* or (self <near/2> heat*))

Results: Your search matched 4 of 713260 documents.

Terms Searched: (integrity or reliability) and (layout or placement or floorplan* or floor-plan*) and (electromigrat* or (self <near/2> heat*))

Results: Your search matched 19 of 713260 documents.

Terms Searched: (transistor <near/4> folding) and (signal <near/10> (reliability or integrity))

Results: Your search matched [0] of [714343] documents.

Terms Searched: (transistor <near/4> folding)

Results: Your search matched 24 of 714315 documents.